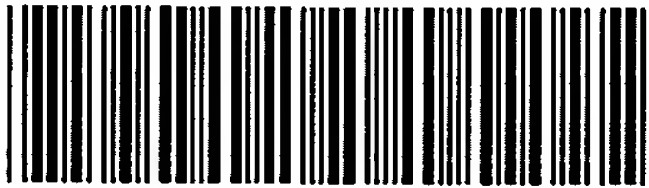


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/633,642	FURUKAWA ET AL.	
	Examiner	Art Unit	
	Rick K. Chang	3729	

SEARCHED			
Class	Subclass	Date	Examiner
29	610.1,611,612	9/6/2005	RC
338	195,314		
	225D		
	22R,22SD		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
east search	9/6/2005	RC